

PATDD

Subject Coverage

- All areas of science and technology, i.e. all classes of the International Patent Classification
-

File Type

Bibliographic

Features

Thesaurus	None		
Alerts (SDIs)	Not available		
CAS Registry Number® Identifiers	<input type="checkbox"/>	Page Images	<input type="checkbox"/>
Keep & Share	<input checked="" type="checkbox"/>	SLART	<input checked="" type="checkbox"/>
Learning Database	<input type="checkbox"/>	Structures	<input type="checkbox"/>

Record Content

- Bibliographic data, abstracts, International Patent Classification Codes, and supplementary terms.
 - Patent publications published by the former Patent Office of the former German Democratic Republic (GDR) from 1981 until October 2, 1990. Also, the database contains the bibliographic data of patents granted according to the patent law of the GDR published by the German Patent and Trademark Office from October 3, 1990.
-

File Size

- 119,437 citations
-

Coverage

1981-2004

Updates

Closed file

Language

German

Database Producer

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 Zweibrückenstr. 12
 80331 München
 Germany
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 Fax: +49 89/2195-2221
 Copyright Holder

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Fax: +49-7247-808-259
Email: helpdesk@fiz-karlsruhe.de

Sources

- Patent publications according to the patent law of the former GDR (DD-patents)
-

User Aids

- Online Helps (HELP DIRECTORY lists all help messages available)
 - STNGUIDE
-

Cluster

- ALLBIB
- AUTHORS
- CORPSOURCE
- HPATENTS
- PATENTS

STN Database Cluster information:

<http://www.stn-international.com/en/customersupport/customer-support#cluster+%7C+subjects+%7C+features>

PATDD contains two database segments: S1 (Segment 1, First Publications) and S2 (Segment 2, Second Publications). Using the field /FS (File Segment) and the proximity operator (L) you may restrict a search to one single segment. Furthermore, segment-specific predefined display formats are available.

Search and Display Field Codes

Fields that allow left truncation are indicated by an asterisk (*).

General Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from title (TI), abstract (AB) and supplementary term (ST) fields)	None or /BI	S WECHSELSPANNUNGSVOLTMETER S STATISCH?(L)MOMENT# S ?AKTIV?	TI, AB, ST
Accession Number	/AN	S 85:265565 /AN	AN
Application Country (1)	/AC	S DD/AC	AI
Application Date (1,2)	/AD	S DD/AI S 841100-841200/AD S 19841129/AI	AI
Application Information	/AI	S DD84-270072/AI	AI
Application Kind Code	/AK	S DDA/AK S DDA/AI	AI
Application Month (1,2)	/AMO	S 198410-198412/AMO S 198411/AI	AI
Application Number (1)	/AP	S DD84-270072/AP S DD84-270072/AI	AI
Application Number INPADOC (2)	/API	S DD84 270072/API	All
Application Year (1,2)	/AY	S 1984-1985/AY S 1984/AY	AI
Document Type	/DT (or /TC)	S P/DT AND VOLTMETER	DT
Entry Date (2)	/ED	S 19920616-19920723/ED	ED
Entry Week (2)	/EW	S 199209/EW	EW
Field Availability	/FA	S RLI/FA AND L7	FA
File Segment	/FS	S VOLTMETER(L)DIGITAL(L)NP/FS	FS
Inventor (Author) (3)	/IN (or /AU)	S VIKTOR LITVICH/IN	IN
Inventor Address (Country Code)	/INA	S SU/INA	INA
Inventor, String	/IN.S	S LITVIN?/IN.S	IN
Inventor, Word (3)	/IN.W	S LITVIN VIKTOR/IN.W	IN
IPC (contains ICM and ICS) (4)	/IC	S H03M001-00/IC S H03M/IC	IC
IPC Main Group Range Searchable (2,4)	/MGR	S H03M/ICM(S)1-5/MGR	not displayed
IPC Sub Group Range Searchable (2,4)	/SGR	S H03M001/IC(S)00000-01000/SGR	not displayed
IPC, Main (4)	/ICM	S H03M001-00/ICM	ICM
IPC, Secondary (4)	/ICS	S H03M/ICS	ICS
Language (code and text)	/LA	S DE/LA	LA
Patent Assignee (Corporate Source) (3)	/PA (or /CS)	S KPI IMENI LETIJA/PA S IMENI/PA(S)ANM/PA	PA
Patent Assignee INPADOC Standard	/PAS	S CARL ZEISS/PAS	PAS
Patent Assignee INPADOC Standard, Word	/PAS.W	S ZEISS/PAS.W	PAS

Search and Display Field Codes

Search Field Name	Search Code	Search Examples	Display Codes
Patent Assignee INPADOC Standard, String	/PAS.S	S ZEISS CARL JENA GMBH/PAS.S	PAS
Patent Assignee, Address (Country Code)	/PAA	S DD/PAA AND H03M001/IC	PAA
Patent Assignee, String	/PA.S	S TECHNISCHER BETRIEB KERAMIK/PA.S	PA
Patent Assignee, Word (3)	/PA.W	S OTTO VON GUERICKE/PA.W	PA
Patent Country (1)	/PC	S DD/PC	PI
Patent Information	/PI (or /PII)	S DD/PI	PI
Patent Information Publication Type	/PIT	S (DD256252(S)A3)/PI	PIT
Patent Kind Code (1)	/PK	S DDA3/PIT	PI
Patent Month (1,2)	/PMO	S A3/PK	PI
Patent Number (Patent Number INPADOC) (1)	/PN (or /PNI)	S A3/PI	PI
Priority Country (1)	/PRC	S 8802-8806/PMO	PRAI
Priority Date (1,2)	/PRD	S DD199662 AA/PN	PRAI
Priority Date, First (1,2)	/PRDF	S DD296442/PI	PRAI
Priority Information	/PRAI	S SU/PRC	PRAI
Priority Kind Code	/PRK	S SU/PRAI	PRAI
Priority Month (2)	/PRMO	S 840415/PRD	PRAI
Priority Number (1)	/PRN	S 19840415/PRD	PRAI
Priority Number INPADOC (1)	/PRNI	S 19840415/PRAI	PRAI
Priority Year (1,2)	/PRY	S 840410-840500/PRDF	PRAI
Priority Year, First (1,2)	/PRYF	S 19840415/PRAI	not displayed
Publication Date (1,2)	/PD	S SU84-3424674/PRAI	PI
Publication Year (1,2)	/PY	S DEU/PRK	PI
Related Application Information	/RLI (or /RLN)	S 8401-8410/PRMO	RLI
Supplementary Term	/ST	S 198404/PRAI	ST
Supplementary Word	/SW	S SU84-3424674/PRN	ST
Title	/TI	S SU84-3424674/PRAI	TI
Update Date (2)	/UP	S SU84 3424674/PRNI	UP
		S 1984-1985/PRY	
		S 1984/PRAI	
		S 1983-1984/PRYF	
		S 1984/PRAI	
		S 880500-880520/PD	
		S 19880504/PI	
		S 1988-1989/PY	
		S 1988/PI	
		S SU1061679/RLI	
		S MOMENT, STATISCH/ST	
		S EFFEKTIVWERT/SW	
		S WECHSELSPANNUNGSVOLTMETER/TI	
		S UP=JUN 1992	

(1) Also searchable in the corresponding collective field (/AI, /All, /PI, /PRAI, /PRII). Dates (e.g. from the fields /AD, /AMO) are searchable in the collective fields only as alphanumeric data with the year expressed in four letters (e.g. 199010/AI). For numeric search, use the corresponding date fields (e.g. /AD, /AMO).

(2) Numeric search field that may be searched with numeric operators or ranges.

(3) Search with implied (S) proximity is possible. (A) and (W) proximity operators are not allowed.

(4) IPC Main Group /MGR and Subgroup /SGR are range searchable. Groups from the same IPC are linked with (S) proximity (compare Search Example).

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI IN. The fields are displayed or printed in the order requested.

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB	Abstract	D TI AB 1-5
AI	Application Information	D AI
AII	Application Information INPADOC	D AII
AN	Accession Number	D L3 AN
DT (TC)	Document Type	D DT LA
ED	Entry Date (STN)	D ED
EW	Entry Week	D EW
FA	Field Availability	D FA
FS	File Segment	D FS
IC	IPC (format contains ICM, ICS)	D IC
ICM	IPC, Main	D ICM
ICS	IPC, Secondary	D ICD
IN (AU)	Inventor (INC, INO)	D IN
INA	Inventor Address	D INS
LA	Language	D LA
PA (CS)	Patent Assignee (PAC, PAO)	D PA
PAA	Patent Assignee Address	D PAA
PAS	Patent Assignee INPADOC Standard	D PAS
PI (PII)	Patent Information	D PI
PIT	Patent Information Publication Type	D PIT
PRAI	Priority Information	D PRAI
PRII	Priority Information INPADOC	D PRII
RLI (RLN)	Related Application Information	D RLI
ST	Supplementary Term	D ST
TI	Title	D TI
UP	Update Date	D UP
ALL	AN, ED resp. UP, EW, FS, TI, IN, INA, PA, PAS, PAA, DT, LA, PIT, PI, AI, RLI, PRAI, IC (ICM, ICS), AB, ST, FA	D ALL
ALL.S1	ALL for database segment S1	D ALL.S1
ALL.S2	ALL for database segment S2	D ALL.S2
IALL	ALL, indented with text labels	D IALL
IALL.S1	ALL.S1, indented with text labels	D IALL.S1
IALL.S2	ALL.S2, indented with text labels	D IALL.S2
BIB	AN, ED resp. UP, EW, FS, TI, IN, INA, PA, PAS, PAA, DT, LA, PIT, PI, AI, RLI, PRAI	D BIB
BIB.S1	BIB for database segment S1	D BIB.S1
BIB.S2	BIB for database segment S2	D BIB.S2
IBIB	BIB, but indented with text labels	D IBIB
IBIB.S1	BIB.S1, indented with text labels	D IBIB.S1
IBIB.S2	BIB.S2, indented with text labels	D IBIB.S2
IND	AN, ED resp. UP, EW, FS, IC (ICM, ICS), ST	D IND
IND.S1	IND for database segment S1	D IND.S1
IND.S2	IND for database segment S1	D IND.S2
IPC	IC (ICM, ICS)	D IPC
STD	AN, ED resp. UP, EW, FS, TI, IN, INA, PA, PAS, PAA, DT, PIT, PI, AI, RLI, PRAI, IC (ICM, ICS), ST (STD is the default)	D STD
STD.S1	STD for database segment S1	D STD.S1
STD.S2	STD for database segment S2	D STD.S2

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
ISTD ISTD.S1 ISTD.S2 TRIAL (TRI, SAM) TRIAL.S1 TRIAL.S2	STD, indented with text labels STD.S1, indented with text labels STD.S2, indented with text labels TI, IC (ICM, ICS), ST TRIAL for database segment S1 TRIAL for database segment S2	D ISTD D ISTD.S1 D ISTD.S2 D TRIAL D TRIAL.S1 D TRIAL S2
HIT KWIC OCC	Hit term(s) and field(s) Up to 50 words before and after hit term(s) (KeyWord-In-Context) Number of occurrences of hit term(s) and field(s) in which they occur	D KWIC D OCC

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract	AB	Y (2)	N
Accession Number	AN	Y	N
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Date Derwent	APD	Y	N
Application Kind Code	AK	Y	Y
Application Month	AMO	Y	Y
Application Number	AP (AI)	Y	Y
Application Number INPADOC	API (All)	Y	Y
Application Year	AY	Y	Y
Document Type	DT (TC)	Y	Y
Entry Week	EW	Y	Y
Field Availability	FA	Y	N
International Patent Classification (IPC)	IPC	Y	Y
	IC	Y	Y
Inventor	IN (AU)	Y (3)	Y
Inventor Address	INA	Y	Y
IPC, Main	ICM	Y	Y
IPC, Secondary	ICS	Y	Y
Language	LA	Y	Y
Occurrence Count of Hit Terms	OCC	N	Y
Patent Assignee	PA (CS)	Y (4)	Y
Patent Assignee Address	PAA	Y	Y
Patent Assignee INPADOC Standard	PAS	Y (5)	Y
Patent Country	PC	Y	Y
Patent Information Publication Type	PIT	Y	Y
Patent Kind Code	PK	Y	Y
Patent Month	PMO	Y	Y
Patent Number	PN (PNI, PI, PII))	Y	Y
Patent Number Derwent	PND	Y	N

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Priority Country	PRC	Y	Y
Priority Date	PRD	Y	Y
Priority Date, First	PRDF	Y (6)	Y
Priority Information INPADOC	PRII	Y (6)	Y
Priority Kind Code	PRK	Y	Y
Priority Month	PRMO	Y	Y
Priority Number	PRN (PRAI)	Y	Y
Priority Number INPADOC	PRNI	Y (6)	Y
Priority Year	PRY	Y	Y
Priority Year, First	PRYF	Y (6)	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y	Y
Related Publication Information	RLN (RLI)	Y	N
Subclass	SCL	Y	N
Subclass Group	SCG	Y	N
Subclass Group Main	SCGM	Y	N
Subclass Group Secondary	SCGS	Y	N
Subclass Main	SCLM	Y	N
Subclass Secondary	SCLS	Y	N
Supplementary Term	ST	Y	Y
Title	TI	Y (default)	Y
Update Date	UP (ED)	Y	N

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT AB.
(2) Appends /BI to the terms created by SELECT.
(3) Appends /IN.S to the terms created by SELECT.
(4) Appends /PA.S to the terms created by SELECT.
(5) Appends /PAS.S to the terms created by SELECT.
(6) SELECT or ANALYZE HIT is not valid with this field.

Sample Records**DISPLAY ALL**

```

DDA5 DD-Patentschrift, Ausschliessungspat., 17.1 DD-PatG
AN 89:335171 PATDD UP 920709 EW 9228 FS S1
TI FASSUNG FUER OPTISCHE ELEMENTE.
IN HAGE,KNUT,DE
INA DE
PA ANM.: VEB CARL ZEISS JENA,DE
INH.: CARL ZEISS JENA,DE
PAS ZEISS JENA VEB CARL
PAA DE
DT Patent; Ausschliessungspatent
LA Deutsch
PIT DDA5 DD-Patentschrift, Ausschliessungspat., 17.1 DD-PatG
PI DD 289827 A5 910508
AI DD 89-335171 A 891204
PRAI DD 89-335171 A 891204
IC ICM (5) G02B007-02
AB Die Erfindung umfasst eine Fassung fuer optische Elemente in einem
Fuellfassungrohr. Mit einfachen Mitteln wird eine eindeutige, jederzeit
reproduzierbare Justierung der einzeln gefassten Linsen im Fassungrohr
erreicht. Zwischen sich gegeneuberliegenden Auszenflaechen von
Linsenfassungen wird ein elastischer Ring eingeklemmt, wodurch das zur
Montage notwendige Passungsspiel ueberwunden wird und die Linsen zentriert
werden. Fig. 2

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PATDD

ST Optik; Objektiv; optisches System; Fassung; Fuellfassung; Justierfassung;
Zentrierung
FA Code Field Name
-----+-----
INA Adresse des Erfinders
PAA Adresse des Anmelders
AB Zusammenfassung
ST Deskriptoren

DISPLAY ALL.S2

ANSWER 1 PATDD COPYRIGHT 2008 DPMA on STN
DDA1 DD-Patentschrift, Wirtschaftspat., 17.1 DD-PatG
DDB1 DD-Patentschrift, Wirtschaftspat., 18.1 DD-PatG

FORTSCHREIBUNG

AN 86:290812 PATDD UP 920709 EW 9228 FS S2
TI VERFAHREN UND ANORDNUNG ZUR BESTIMMUNG DER FLUGWEITE.
IN DEHN ROTFELSER, HEINRICH VON, DD; BARNEKOW, HARALD, DD; SUESS, STEFAN, DD
INA DD
PA ANM.: VEB CARL ZEISS JENA, DD
PAS ZEISS JENA VEB CARL
PAA DD
DT Patent; Wirtschaftspatent
LA Deutsch
PIT DDB1 DD-Patentschrift, Wirtschaftspat., 18.1 DD-PatG
PI DD 266841 B1 900620
AI DD 86-290812 A 860602
PRAI DD 86-290812 A 860602
IC ICM (5) G01B011-14
AB Die Erfindung betrifft ein Verfahren und eine Anordnung zur Bestimmung der Flugweite von sich auf Flug-, Sprung- oder Wurfbahnen bewegenden Koerpern, insbesondere zur Sprungweitenbestimmung von Skispringern. Es soll ein Verfahren und eine Anordnung geschaffen werden, wobei mittels mobiler Ausruestungen ohne zusaetzliche Vorrichtungen an den bewegten Koerpern eine objektive, nachtraeglich ueberpruefbare Weitenbestimmung erfolgt und dabei gleichzeitig eine hohe Stoersicherheit gewaehrleistet ist. Die Aufgabe loest ein Verfahren, bei dem das lagegetreue mathematische Modell der Landebahn mit hinreichend schnellen Kamerabildfolgen korreliert und daraus die Flugweite bestimmt wird, und eine Anordnung, die aus das Profil des Landebereichs beschreibenden Mitteln, mindestens einer die Landeszene aufnehmenden und Bildfolgen liefernden Kamera, deren Daten der inneren und aeusseren Orientierung bekannt und mit den Positionswerten des Kamerastandpunktes abgespeichert sind, einer Auswerteeinrichtung und einer Anzeigeeinheit besteht. Fig. 1
FA Code Field Name
-----+-----
INA Adresse des Erfinders
PAA Adresse des Anmelders
PRAI Prioritaetsinformationen
AB Zusammenfassung

In North America

CAS
STN North America
P.O. Box 3012
Columbus, Ohio 43210-0012 U.S.A.

CAS Customer Center:
Phone: 800-753-4227 (North America)
614-447-3700 (worldwide)
Fax: 614-447-3751
Email: help@cas.org
Internet: www.cas.org

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STN Europe
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Email: helpdesk@fiz-karlsruhe.de
Internet: www.stn-international.com

In Japan

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International Chemical Information)
STN Japan
Nakai Building
6-25-4 Honkomagome, Bunkyo-ku
Tokyo 113-0021, Japan
Phone: +81-3-5978-3601 (Technical Service)
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Fax: +81-3-5978-3600
Email: support@jaici.or.jp (Technical Service)
customer@jaici.or.jp (Customer Service)
Internet: www.jaici.or.jp